

# S603 / S750 set

1 Ohm / 150 Ohm, Conducted RF Measurement acc. IEC 61967-4

**LANGER**  
EMV-Technik



## Short description

The probe set is used to measure conducted emissions 1 Ohm/150 Ohm with the direct coupling method on IC pins. The S603 probe is used for current measurement and the S750 probe is used for voltage measurement.

The measurements with the S603/S750 ensure a high repeatability and comparability of the measurements. The measurements can be performed with the ChipScan-ESA software. The measurement results of all measured pins are saved with the help of the software. It allows systematically and quickly comparison and analysis of the measured data.

## Scope of delivery

- 1x S603, 1 Ohm, RF Current Probe, 0 kHz - 3 GHz acc. to IEC 61967-4
- 1x S750, 150 Ohm, RF Voltage Probe, 100 kHz - 3 GHz acc. to IEC 61967-4
- 1x SMA-SMA 1 m, SMA-SMA Measuring Cable

# S603 / S750 set

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S603/S750 set scope of delivery



Application with S750 RF voltage probe

